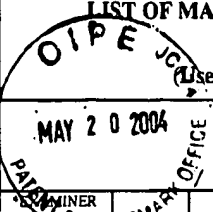


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	INVENTOR'S NAME: Jared ZERBE et al.	EXAMINER: Tung S. Lau
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